

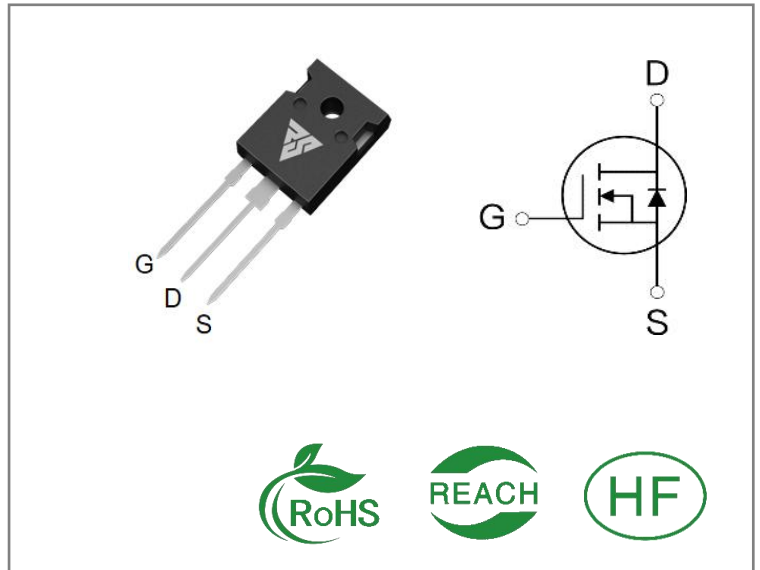
| ID | R _{DS(ON)} (Typ) | VDSS |
|-----|---------------------------|------|
| 30A | 85mΩ | 500V |

Applications:

- Switch Mode Power Supply(SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)

Features:

- Fast switching speed
- 100% avalanche tested
- Improved dv/dt capability


Ordering Information

| Part Number | Package | Marking | Packing | Qty. |
|-------------|----------|----------|---------|--------|
| RS30N50W | T0-247-3 | RS30N50W | Tube | 30 PCS |

Absolute Maximum Ratings T_c= 25°C unless otherwise specified

| Symbol | Parameter | RS30N50W | Units |
|-------------|--|------------|-------|
| VDSS | Drain-to-Source Voltage | 500 | V |
| ID | Continuous Drain Current TC=25°C | 30 | A |
| IDM | Pulsed Drain Current (Note*1) | 120 | |
| PD | Power Dissipation | 320 | W |
| VGS | Gate- to- Source Voltage | ±30 | V |
| EAS | Single Pulse Avalanche Energy L = 10mH,,VDD = 50V, RG = 25Ω | 2800 | mJ |
| TL TPKG | Maximum Temperature for Soldering | 300 260 | °C |
| | Leads at 0.063in(1.6mm)from Case for 10 seconds Package Body for 10 seconds | | |
| TJ and TSTG | Operating Junction and Storage Temperature Range | -55 to 150 | |

* Drain Current Limited by Maximum Junction Temperature

Caution: Stresses greater than those listed in the“ Absolute Maximum Ratings” Table may cause permanent damage to the device.

Thermal Resistance

| Symbol | Parameter | RS30N50W | Units | Test Conditions |
|---------------|---------------------|----------|--------|---|
| R θ JC | Junction-to-Case | 0.38 | °C / W | Drain lead soldered to water cooled heatsink, PD adjusted for a peak junction temperature of + 150 °C |
| R θ JA | Junction-to-Ambient | 40 | | 1 cubic foot chamber, free air. |

OFF Characteristics T_J= 25°C unless otherwise specified

| Symbol | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|--------|-------------------------------------|------|------|------|-------|-------------------|
| BVDSS | Drain- to- source Breakdown Voltage | 500 | -- | -- | V | VGS=0V, ID=250μA |
| IDSS | Drain- to- Source Leakage Current | -- | -- | 1 | μA | VDS=500V, VGS=0V |
| IGSS | Gate- to- Source Forward Leakage | -- | -- | 100 | nA | VGS=30V , VDS=0V |
| | Gate- to- Source Reverse Leakage | -- | -- | -100 | | VGS=-30V , VDS=0V |

ON Characteristics T_J=25°C unless otherwise specified

| Symbol | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|---------|--|------|------|------|-------|-------------------|
| RDS(on) | Static Drain- to- Source On-Resistance(Note*2) | -- | 85 | 120 | mΩ | VGS=10V, ID=15A |
| VGS(TH) | Gate Threshold Voltage | 3 | -- | 4 | V | VGS=VDS, ID=250μA |

Resistive Switching Characteristics Essentially independent of operating temperature

| Symbol | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|---------|----------------------|------|------|------|-------|------------------------------|
| td(ON) | Turn- on Delay Time | -- | 60 | -- | nS | VDS=250V ID=30A RG=25Ω |
| trise | Rise Time | -- | 130 | -- | | |
| td(OFF) | Turn- OFF Delay Time | -- | 100 | -- | | |
| tfall | Fall Time | -- | 91 | -- | | |

Dynamic Characteristics Essentially independent of operating temperature

| Symbol | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|--------|---------------------------------|------|------|------|-------|-------------------------------|
| Ciss | Input Capacitance | -- | 7850 | -- | pF | VGS=0V VDS=25V f=1.0MHz |
| Coss | Output Capacitance | -- | 750 | -- | | |
| Crss | Reverse Transfer Capacitance | -- | 30 | -- | | |
| Qg | Total Gate Charge | -- | 150 | -- | nC | VDS=400V ID=30A VGS=10V |
| Qgs | Gate- to- Source Charge | -- | 36 | -- | | |
| Qgd | Gate-to-Drain(" Miller") Charge | -- | 56 | -- | | |

Source- Drain Diode Characteristics

| Symbol | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|--------|---------------------------|------|------|------|-------|------------------------------------|
| IS | Continuous Source Current | -- | -- | 30 | A | Integral pn- diode in MOSFET |
| ISM | Maximum Pulsed Current | -- | -- | 120 | A | |
| VSD | Diode Forward Voltage | -- | -- | 1.2 | V | IS=15A,VGS=0V |
| trr | Reverse Recovery Time | -- | 500 | -- | nS | VGS=0V IS=30A,di/dt=100 A/μs |
| Qrr | Reverse Recovery Charge | -- | 8.3 | -- | μC | |

Notes:

- * 1. Repetitive rating, pulse width limited by maximum junction temperature.
- * 2. Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty Cycle $\leq 1\%$

Typical Feature Curve

Figure 1. Output Characteristics (T_J = 25°C)

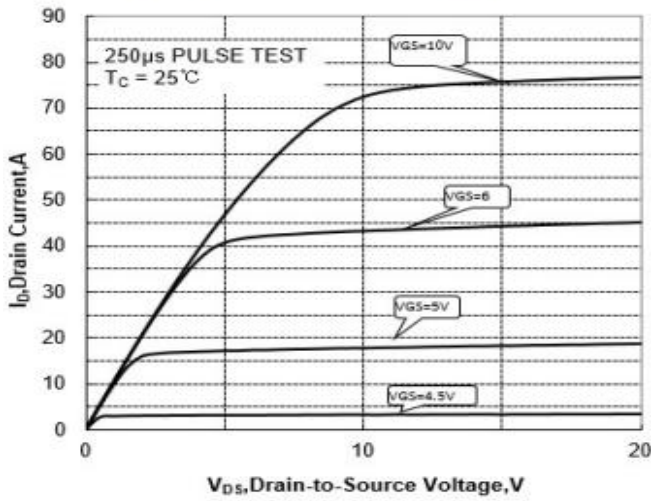


Figure 2. Safe Operating Area

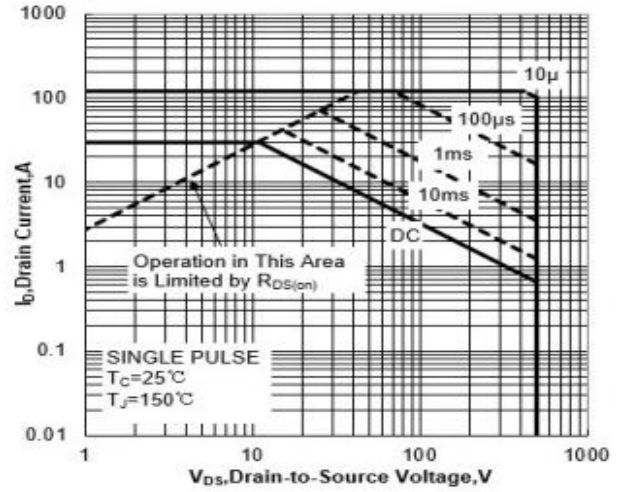


Figure 3. Drain Current vs. Temperature

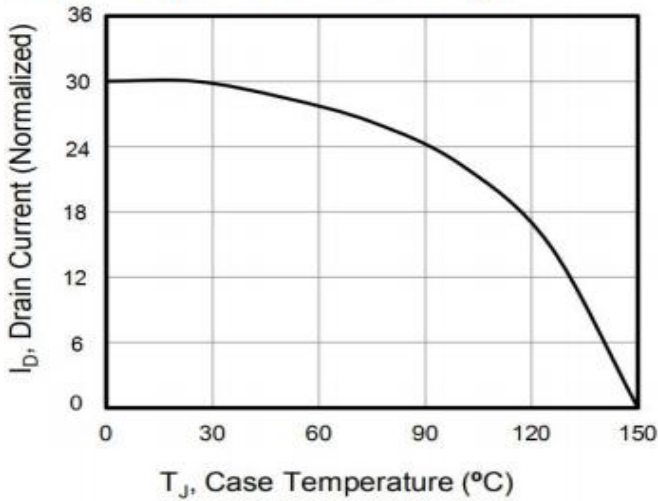


Figure 4. BVDSS Variation vs. Temperature

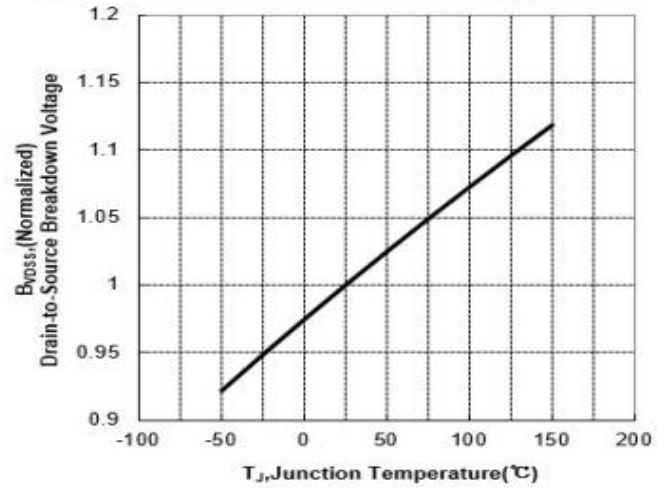


Figure 5. Transfer Characteristics

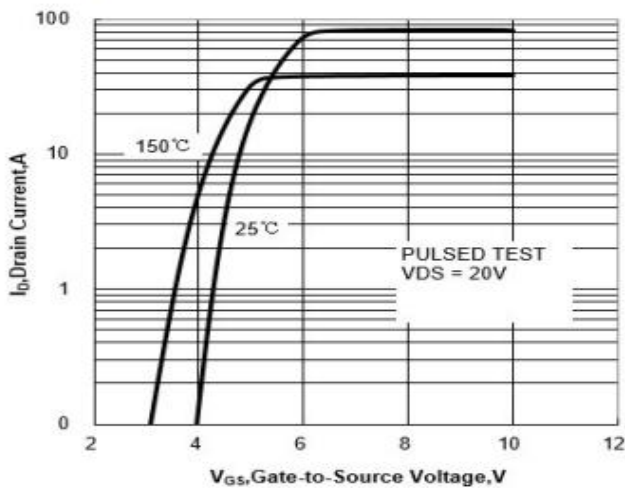


Figure 6. On-Resistance vs. Temperature

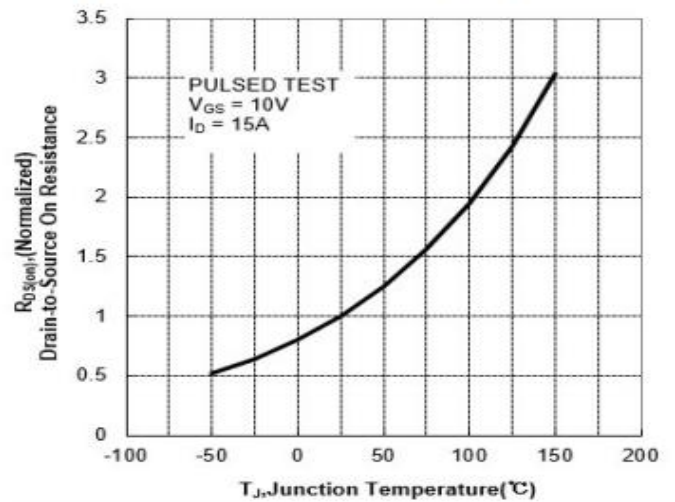


Figure 7. Capacitance

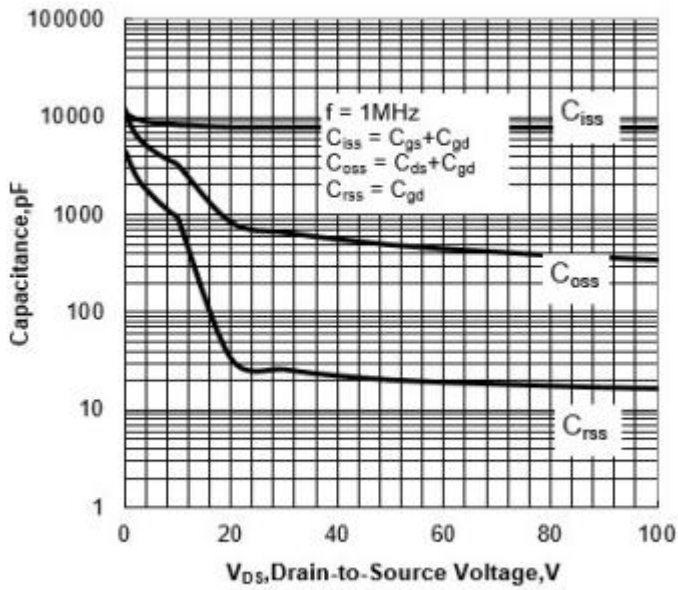


Figure 8. Gate Charge

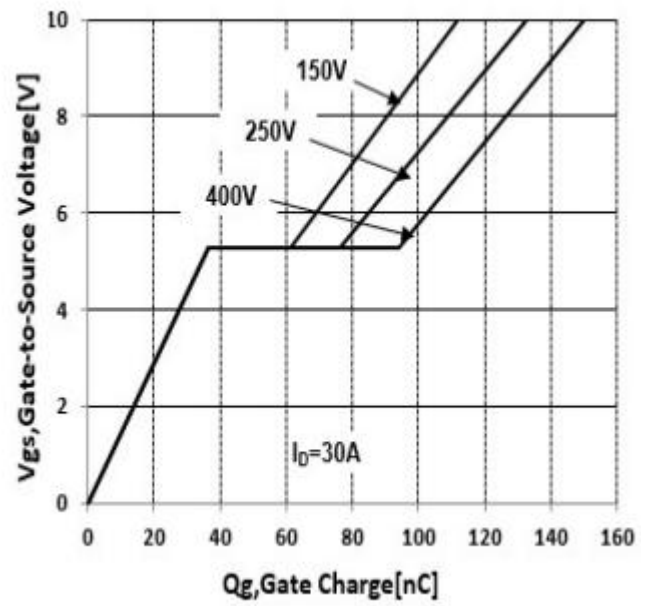
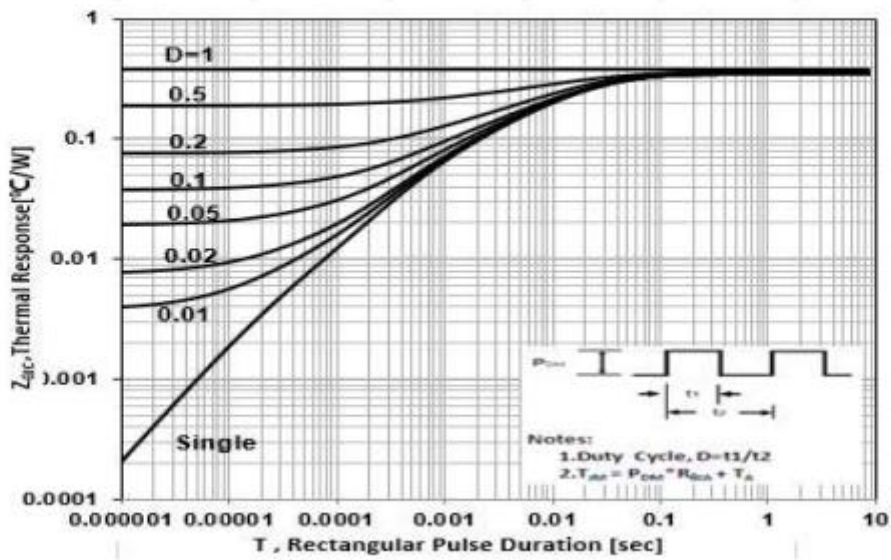


Figure 9. Transient Thermal Impedance



Test Circuits and Waveforms

Figure A: Gate Charge Test Circuit and Waveform

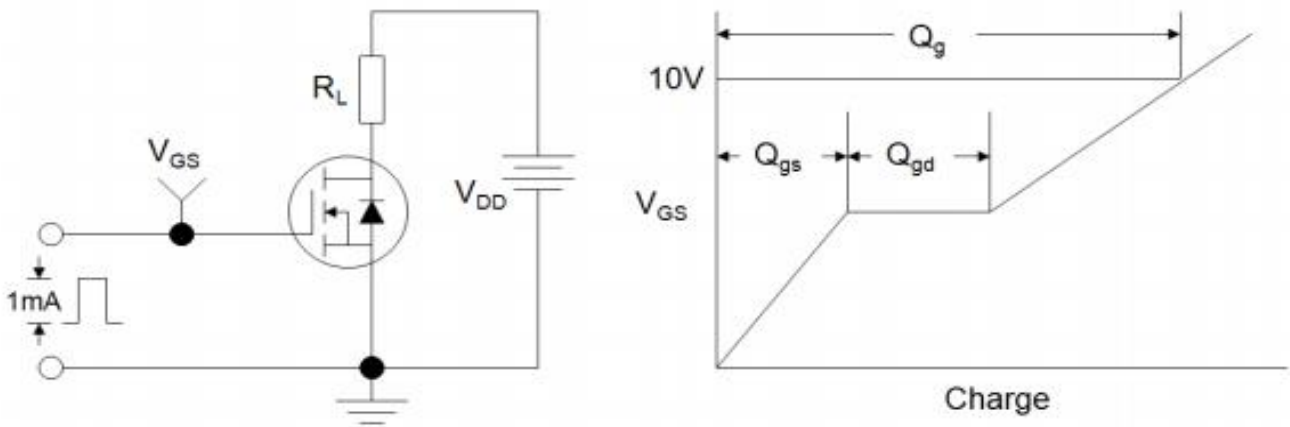


Figure B: Resistive Switching Test Circuit and Waveform

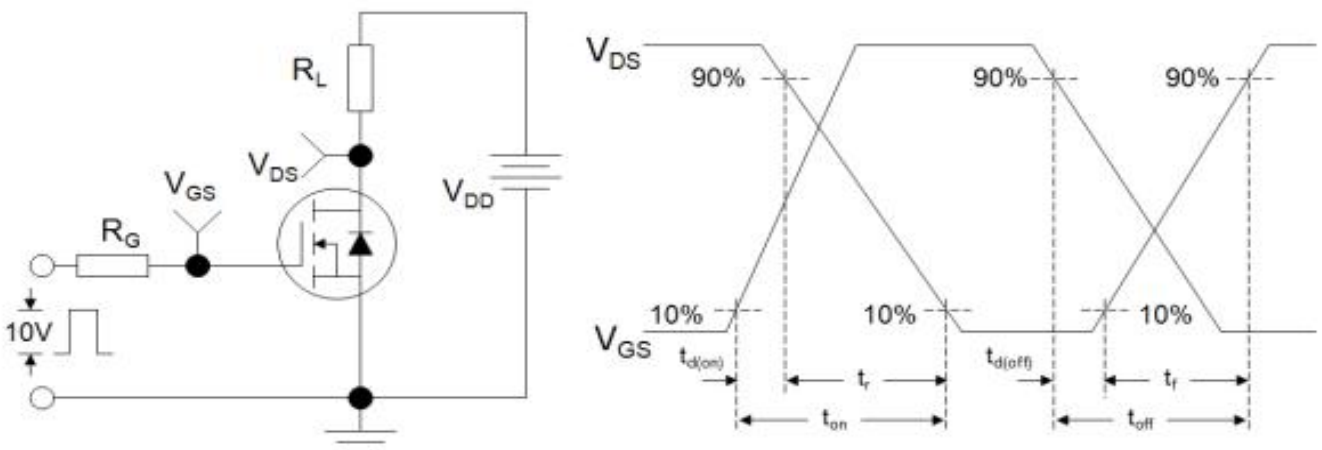
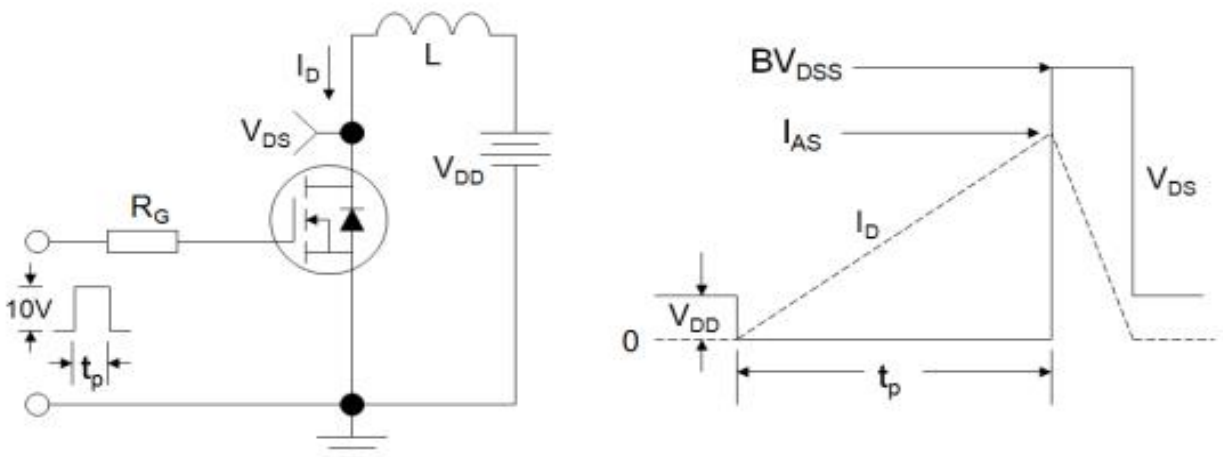
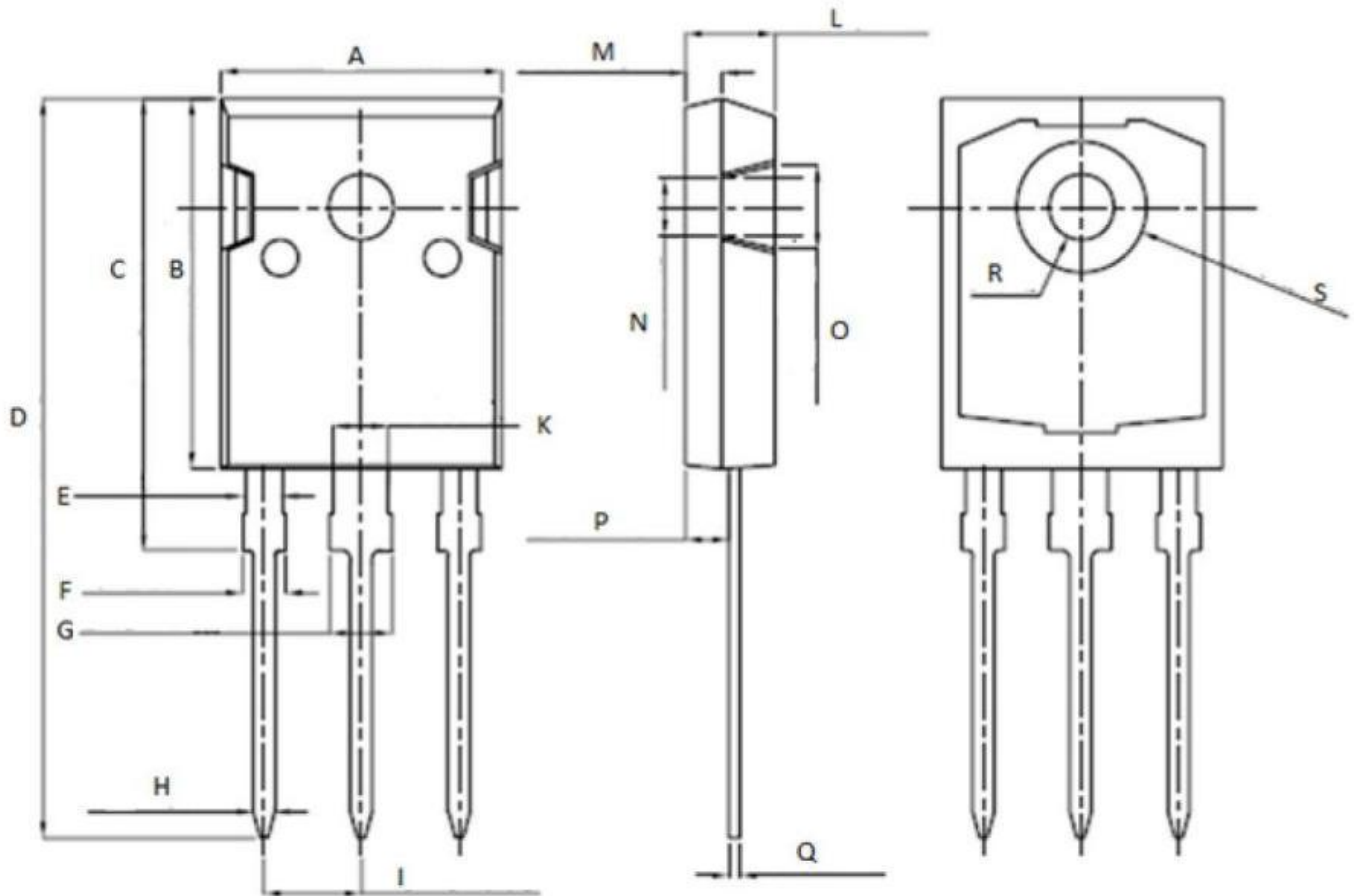


Figure C: Unclamped Inductive Switching Test Circuit and Waveform



Package outline drawing(TO-247 Unit: mm)



| Unit: mm | | |
|----------|-------|-------|
| Symbol | Min. | Max. |
| A | 15.95 | 16.25 |
| B | 20.85 | 21.25 |
| C | 20.95 | 21.35 |
| D | 40.5 | 40.9 |
| E | 1.9 | 2.1 |
| F | 2.1 | 2.25 |
| G | 3.1 | 3.25 |
| H | 1.1 | 1.3 |
| I | 5.40 | 5.50 |

| Unit: mm | | |
|----------|-------|-------|
| Symbol | Min. | Max. |
| K | 2.90 | 3.10 |
| L | 4.90 | 5.30 |
| M | 1.90 | 2.10 |
| N | 4.50 | 4.70 |
| O | 5.40 | 5.60 |
| P | 2.29 | 2.49 |
| Q | 0.51 | 0.71 |
| R | φ 3.5 | φ 3.7 |
| S | φ 7.1 | φ 7.3 |

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